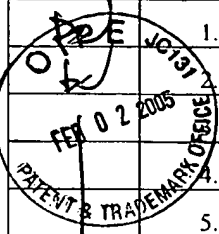
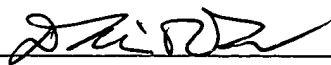


Form PTO-1449		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket No. 5308-394		Serial No. 10/811,350	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Applicant: Gerald H. Negley			
				Filing Date: March 26, 2004		GAU: 2812	
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Examiner Initials	Document No.	Date (m/d/y)	Name	Class	Subclass	Filing Date if Appropriate	
	1.	6,214,107	04/10/2001	Kitabatake	117	95	
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OTHER DOCUMENTS							
20.	Pearson, S.J., "Wet and Dry Etching of SiC," <i>Process Technology for Silicon Carbide Devices</i> , pp. 85-92. Ch. 4 (2002).						

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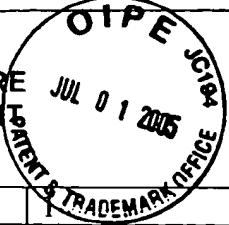


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Substitute form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/811,350		
		Filing Date	March 26, 2004		
		First Named Inventor	Gerald H. Negley		
		Group Art Unit	2812		
		Examiner Name	TBA		
Sheet 1 of 1	Attorney Docket Number	5308-394			

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		Number	Kind Code (if known)		
<i>PN</i>	1.	US-2001/040245	A1	Kawai	11-15-2001
<i>PN</i>	2.	US-2002/123164	A1	Slater et al.	09-05-2002
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		Office	Number	Kind Code (if known)			
<i>PN</i>	4.	DE	35 06 995	A1	Siemens AG	08-26-1986	No
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OTHER NON PATENT LITERATURE DOCUMENTS					T
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			
<i>PN</i>	6.	Alok et al. "A Novel Method for Etching Trenches in Silicon Carbide" <i>Journal of Electronic Materials</i> 24(4): 311-314 (1995)			
<i>PN</i>	7.	Dogan et al. "4H-SiC Photoconductive Switching Devices for Use in High-Power Applications" <i>Applied Physics Letters</i> 82(18): 3107-3109 (2003)			
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Examiner Signature	<i>Lawrence</i>	Date Considered	8/2/06
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